## Notice of References Cited Application/Control No. 10/674,834 Examiner Anh Ly Applicant(s)/Patent Under Reexamination BITSCH ET AL. Page 1 of 1

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	Application/Control No.	Applicant(s)/Patent Under Reexamination
Index of Claims	10674834	BITSCH ET AL.
	Examiner	Art Unit
	Ly, Anh	2162

<b>✓</b>	Rejected	-	Cancelled	N	Non-Elected	A	Appeal
=	Allowed	÷	Restricted	I	Interference	0	Objected

☐ Claims renumbered in the same order as presented by applicant						☐ CPA	☐ T.D.	☐ R.1.47	7
CLAIM		DATE							
Final	Original	04/18/2007	I						
	37	N						-	
	38	N							
	39	N							
	40	N							

U.S. Patent and Trademark Office Part of Paper No.: 20070418